



520.41064X00/NT0550US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Akira HAMAMATSU *et al.*  
Application No.: 10/050,776  
Filed: 18 January 2002  
For: APPARATUS AND METHOD FOR INSPECTING DEFECTS  
Art Unit: 2877  
Examiner: M.P. Stafira  
Conf. No: 9567

**PETITION FOR EXTENSION OF TIME**


Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-14501

18 July 2005

Sir:

In the matter of the above-identified application, Applicant respectfully petitions the Commissioner for an extension of time set by the Notice of Appeal filed April 15, 2005. A Request for Continued Examination is submitted concurrently herewith. Please charge any fee deficiency to ATSK Deposit Account No. 01-2135.

Respectfully submitted,

  
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Concurrent Filings:  
Request for Continued Examination  
Declaration Under 37 CFR 1.132